

Tetrakis(2-methyl-2-phenylpropyl)stannane at 150 K

John Nicolson Low and J. L. Wardell

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Tetrakis(2-methyl-2-phenylpropyl)-
stannane at 150 KJohn Nicolson Low^{a*} and J. L. Wardell^b^aDepartment of Applied Physics and Electronic and Mechanical Engineering,
University of Dundee, Nethergate, Dundee DD1 4HN, Scotland, and ^bDepartment of
Chemistry, University of Aberdeen, Meston Walk, Old Aberdeen AB24 3UE,
Scotland

Correspondence e-mail: j.n.low@dundee.ac.uk

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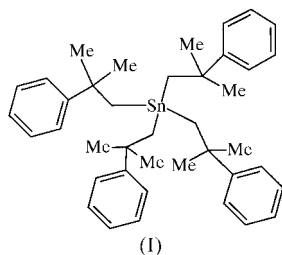
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The structure of the title compound, tetrakis(2-methyl-2-phenylpropyl)stannane, (PhCMe₂CH₂)₄Sn, has been determined at 293 K by Reuter & Pawlak (1998). This present determination was carried out at 150 K and as a result gives cell, coordinate and displacement parameters with much reduced s.u.'s. As is pointed out in the the above paper, the bonds and angles are similar to those in related Sn compounds although it is worth emphasizing that there are no intra- or intermolecular ring–ring interactions but that there are a number of C–H...Cg(π -ring) interactions at the 3.0 Å level.

Comment

Examination of the structure (I) with *PLATON* (Spek, 1999) showed that there were no solvent-accessible voids in the crystal lattice.



Experimental

Tetrakis(2-methyl-2-phenylpropyl)stannane was prepared from the Grignard reagent, from PhCMe₂CH₂Cl and Mg in

Et₂O and SnCl₄ in benzene. It was recrystallized as colourless crystals from petroleum ether (60–80°C) and had a melting point of 94–96°C.

Crystal data

[Sn(C₁₀H₁₃)₄]
M_r = 651.51
Monoclinic, *P*2₁/*c*
a = 13.9224 (4) Å
b = 9.9590 (2) Å
c = 25.6952 (6) Å
 β = 104.5178 (14)°
V = 3448.96 (15) Å³
Z = 4

D_x = 1.255 Mg m⁻³
Mo *K*α radiation
Cell parameters from 7414
reflections
 θ = 1.51–27.48°
 μ = 0.766 mm⁻¹
T = 150.0 (1) K
Lath, colourless
0.300 × 0.100 × 0.025 mm

Data collection

KappaCCD diffractometer
 φ scans and ω scans with κ offset scans
Absorption correction: multi-scan
(SORTAV; Blessing, 1995, 1997)
*T*_{min} = 0.927, *T*_{max} = 0.973
24777 measured reflections

7414 independent reflections
5147 reflections with *I* > 2σ(*I*)
*R*_{int} = 0.064
 θ _{max} = 27.48°
h = -17 → 17
k = -12 → 12

Refinement

Refinement on *F*²
R [*F*² > 2σ(*F*²)] = 0.038
wR (*F*²) = 0.088
S = 0.989
7414 reflections
378 parameters

H-atom parameters constrained
w = 1/[σ²(*F_o*²) + (0.0265*P*)² +
1.4792*P*] where *P* = (*F_o*² + 2*F_c*²)/3
(Δσ)_{max} = 0.004
Δρ_{max} = 0.828 e Å⁻³
Δρ_{min} = -0.737 e Å⁻³

Molecule (1) crystallized in the monoclinic system; space group *P*2₁/*c* from the systematic absences. H atoms were treated as riding atoms with C–H 0.90–0.98 Å.

Data collection: KappaCCD server software (Nonius, 1997); cell refinement: DENZO (Otwinowski & Minor, 1997); data reduction: DENZO (Otwinowski & Minor, 1997); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997a); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997b); software used to prepare material for publication: *SHELXL97* and *WordPerfect* macro PRPKAPPA (Ferguson, 1999).

X-ray data were collected at the EPSRC, X-ray Crystallographic Service, University of Southampton using an Enraf–Nonius KappaCCD diffractometer. The authors thank the staff for all their help and advice.

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